

Notice of References Cited	Application/Control No. 10/624,524	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Nhan T. Tran	Art Unit 2622	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	D	US-6,466,202	10-2002	Suso et al.	455/575.3
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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